

NATIONAL INSTITUTE OF TECHNOLOGY ROURKELA-769008 (ODISHA)

An Institute of National Importance under Ministry of HRD, GOI

NOTICE INVITING TENDER

Tender Notification No: NITR/PW/CH/2021/253 Dated: 12/03/2021

The National Institute of Technology, Rourkela invites bids from the eligible bidders for procurement and installation of **Emitter Low Diff Mono (FEG Tip) for FEI 300 kv High Resolution Transmission Electron Microscope** at Department of Chemical Engineering, NIT Rourkela.

Last date of Submission of Bid : 31/03/2021 by 11:00 AM

Opening date of Techno-commercial Bid: 01/04/2021 at 11:00 AM

For Details: https://nitrkl.ac.in/OldWebsite/Jobs Tenders/9Equipment/Default.aspx

Contact: Prof. S.Paria,

Department of Chemical Engineering National Institute of Technology

Rourkela-769008, Odisha Phone: 0661-2462262 Email ID: sparia@nitrkl.ac.in

Bidding through: https://eprocure.gov.in/eprocure/app

Sd/-

REGISTRAR



NATIONAL INSTITUTE OF TECHNOLOGY ROURKELA-769008, ODISHA

OPEN TENDER NOTICE NO.: NITR/PW/CH/2021/253 Dated: 12/03/2021)

Procurement_and installation of Emitter Low Diff Mono (FEG Tip) for FEI 300 kv High Resolution Transmission Electron Microscope at NIT Rourkela

Item No	DESCRIPTION	Quantity
1	Emitter Low Diff Mono (FEG Tip) for FEI 300 kv High Resolution Transmission Electron Microscope	1 unit

- 1. Quantity required : As mentioned above (All information regarding technical specification provided in the Annexure-II in Tender Document)
- 2. Delivery : Within **90 days** from the date of purchase order
- 3. Last Date of submission of Bid : 31/03/2021 by 11:00 AM
- 4. Date of opening of Techno-commercial: 01/04/2021 at 11:00 AM
- 5. The firm should not have been black listed at any time.
- 6. The submission of following bids by the tenderer should be through https://eprocure.gov.in/eprocure/app Please follow the guidelines as per the portal.

Procurement_and installation of Emitter Low Diff Mono (FEG Tip) for FEI 300 kv High Resolution Transmission Electron Microscope

(Open Tender Notice No.: NITR/PW/CH/2021/253 Dated: 12/03/2021)

Due on 31/03/2021 by 11:00 AM

- 7. **Liquidated damage clause** will be charged for any delay in supply of goods.
- 8. The validity of the tender shall be **90 days** from the date of opening of techno-commercial bid.
- 9. Detailed advertisement including all tender documents is also available in our website at http://nitrkl.ac.in/OldWebsite/Jobs Tenders/9Equipment/Default.aspx.
- **10.** NIT reserves the right to qualify or deny prequalification of any or all applicants without assigning any reasons.

(REGISTRAR) NIT, Rourkela Fax No- 0661-2462022 Ph. No -0661-2462021

Technical Specification of Emitter low Diff Mono (TEM FEG Tip)

Emitter low Diff Mono (TEM FEG Tip) for 300kv High Resolution Transmission Electron Microscope, Model Tecnai G2 F30 S-TWIN Serial No-D949: This module is used in FEI Transmission Electron Microscope. In microscope, a field emission gun is used to produce an electron beam that is smaller in diameter, more coherent and with up to three orders of magnitude greater current density or brightness than can be achieved with conventional thermionic emitters such as tungsten or lanthanum hexaboride tipped filaments. The result in transmission electron microscopy is significantly improved signal to noise ratio and spatial resolution, and greatly increase emitter life and reliability compared with thermionic devices.

The emitter module is fixed inside the gun assembly and supply will be connected to it electrons emitted from this module will be accelerated towards the specimen by applying the acceleration voltage to the complete assembly.

Warranty:

3 months from the date of receipt at site and if the product lifetime is less than 50% of expected lifetime, it will be replace free of cost. Please enclose warranty certificate with invoice.

Other clause:

EMITTER LOW DIFF MONO is quoted on exchange price. The installation of the part to be done within 15 days from the date of receipt at site and the defective part will be handover to your engineer with a proper gate pass to take out the defective part.
